

■Features

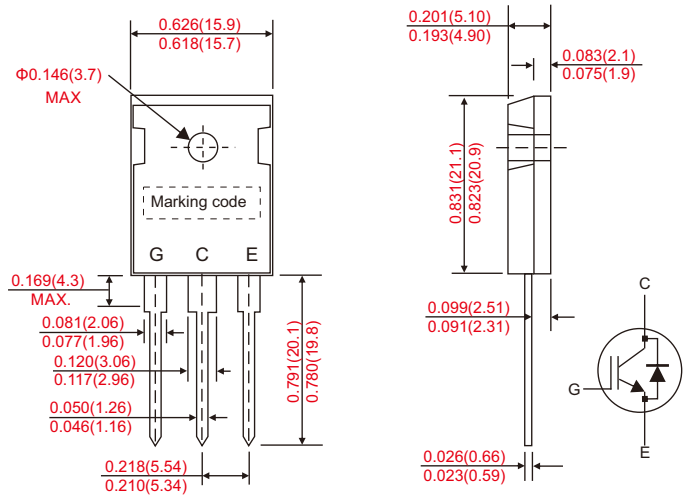
- Positive temperature Co-efficient for easy parallel operation.
- High current capability.
- High input impedance.
- Suffix "G" indicates Halogen-free part, ex.CIF25P120PG.

■ Mechanical data

- Epoxy : UL94-V0 rated flame retardant.
- Case : JEDEC TO-247 molded plastic body over passivated chip.
- Lead : Axial leads, solderable per MIL-STD-202, Method 208 guaranteed.
- Polarity: Color band denotes cathode end .
- Mounting Position : Any .
- Weight : Approximated 5.60 gram .

■Outline

TO-247



■Maximum ratings

Rating at 25 °C ambient temperature unless otherwise specified.

Parameter	Conditions	Symbol	CIF25P120P	UNIT
Marking code			CIF25P120P	
Collector to Emitter Voltage		V_{CE}	1200	V
Collector Current	$T_c = 25^{\circ}\text{C}$ $T_c = 100^{\circ}\text{C}$	I_C	50 25	A
Pulsed collector current		I_{Cpuls}	75 ^{*2}	A
RBSOA current	$V_{CE} < 1200\text{V}$, $T_J \leq 150^{\circ}\text{C}$	I_{Cpeak}	75 [*]	A
Diode Forward Current	$T_c = 25^{\circ}\text{C}$ $T_c = 100^{\circ}\text{C}$	I_F	30 15	A
Pulsed diode current		I_{Fpuls}	40 [*]	A
Gate to Emitter Voltage		V_{GE}	± 20	V
Power dissipation	$T_c = 25^{\circ}\text{C}$ $T_c = 100^{\circ}\text{C}$	P_{tot}	298 119	W
Operating Junction Temperature		T_J	-55 ~ +150	$^{\circ}\text{C}$
Storage Temperature Range		T_{STG}	-55 ~ +150	$^{\circ}\text{C}$

Note : 1.Test Standard to follow JESD-022 .
2.Mark(*) is to estimate numerical value.
3.Test Cycle<1000 ; Test Timing>1s.

■ Thermal characteristics

PARAMETER	CONDITIONS	Symbol	MIN.	TYP.	MAX.	UNIT
Thermal Resistance	Junction to Case	$R_{\theta JC}$			0.42	K/W
Diode thermal resistance	chip case	$R_{\theta JCD}$			1.2	
Thermal Resistance	Junction to Ambient	$R_{\theta JA}$			40	

■ Electrical characteristics(AT $T_A = 25^\circ\text{C}$ unless otherwise noted)

On characteristics

PARAMETER	CONDITIONS	Symbol	MIN.	TYP.	MAX.	UNIT
Collector to Emitter Breakdown Voltage	$V_{GE} = 0V, I_C = 1.5mA$	$V_{(BR)CES}$	1200			V
Collector to Emitter Saturation Voltage	$V_{GE} = 15V, I_C = 25A$ $T_J = 25^\circ\text{C}$ $T_J = 150^\circ\text{C}$	$V_{CE(sat)}$		2.25 2.6	2.4	
Diode forward voltage	$V_{GE} = 0V, I_F = 15A$ $T_J = 25^\circ\text{C}$ $T_J = 150^\circ\text{C}$	V_F		1.87 1.5		
Gate threshold voltage	$I_C = 1mA, V_{CE} = V_{GE}$	$V_{GE(th)}$	5.0	6.1	7.0	
Collector Cut-Off Current	$V_{CE} = 1200V, V_{GE} = 0V$ $T_J = 25^\circ\text{C}$ $T_J = 150^\circ\text{C}$	I_{CES}			0.1 2	mA
G-E Leakage Current	$V_{CE} = 0V, V_{GE} = 20V$	I_{GES}			100	nA
Transconductance	$V_{CE} = 20V, I_C = 25A$	gFS		10.5		S

Dynamic characteristics

PARAMETER	CONDITIONS	Symbol	MIN.	TYP.	MAX.	UNIT
Input Capacitance	$V_{CE} = 25V$	C_{iss}		3480		pF
Output Capacitance	$V_{GE} = 0V$	C_{oss}		99		
Reverse Transfer Capacitance	$f = 1MHz$	C_{rss}		55		
Total Gate Charge	$V_{CC} = 900V, I_C = 25A, V_{GE} = 15V$	Q_G		tbtd		nC

Switching characteristics						
PARAMETER	CONDITIONS	Symbol	MIN.	TYP.	MAX.	UNIT
Turn-On Delay Time	$T_J = 25\text{ }^{\circ}\text{C}$ $V_{CC} = 600\text{V}, I_C = 25\text{A}$ $V_{GE} = 15/0\text{V}$ $R_G = 15\Omega$ $L_{load} = 500\mu\text{H}$	$t_{d(on)}$		45		ns
Rise Time		t_r		50		
Turn-Off Delay Time		$t_{d(off)}$		165		
Fall Time		t_f		98		
Turn-On Switching Loss		E_{on}		1.33		mJ
Turn-Off Switching Loss			E_{off}		0.82	
Total Switching Loss			E_{ts}		2.15	
Turn-On Delay Time	$T_J = 150\text{ }^{\circ}\text{C}$ $V_{CC} = 600\text{V}, I_C = 25\text{A}$ $V_{GE} = 15/0\text{V}$ $R_G = 15\Omega$ $L_{load} = 500\mu\text{H}$	$t_{d(on)}$		35		ns
Rise Time		t_r		52		
Turn-Off Delay Time		$t_{d(off)}$		200		
Fall Time		t_f		225		
Turn-On Switching Loss		E_{on}		1.35		mJ
Turn-Off Switching Loss			E_{off}		1.60	
Total Switching Loss			E_{ts}		2.95	
Switching characteristics						
PARAMETER	CONDITIONS	Symbol	MIN.	TYP.	MAX.	UNIT
Reverse recovery time	$T_J = 25\text{ }^{\circ}\text{C}$ $V_{CC} = 600\text{V}, I_F = 15\text{A}$ $di_F/dt = 600\text{A}/\mu\text{s}$	t_{rr}		280		ns
Reverse recovery charge		Q_{rr}		5.5		nC
Repetitive Peak Reverse Current		I_{rm}		40		A
Reverse recovery time	$T_J = 150\text{ }^{\circ}\text{C}$ $V_{CC} = 600\text{V}, I_F = 15\text{A}$ $di_F/dt = 500\text{A}/\mu\text{s}$	t_{rr}		120		ns
Reverse recovery charge		Q_{rr}		1.30		nC
Repetitive Peak Reverse Current		I_{rm}		20		A

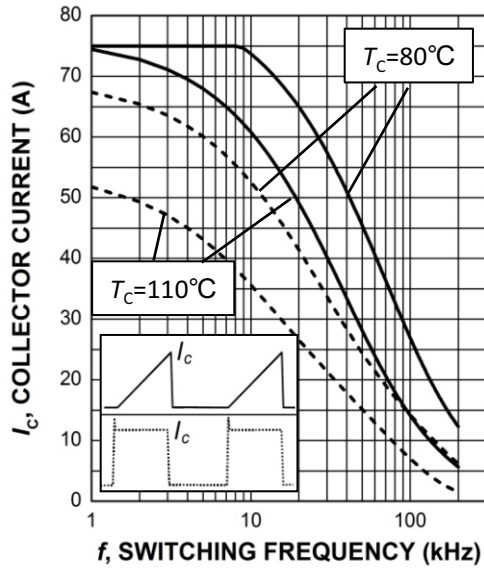


Figure 1. Collector current as a function of switching frequency
 $(T_j \leq 150^\circ\text{C}, D = 0.5, V_{CE} = 600\text{V}, V_{GE} = 0/+15\text{V}, R_G = 15\Omega)$

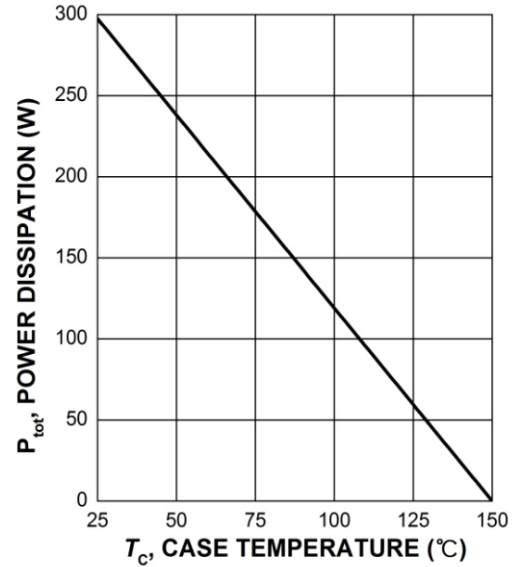


Figure 2. Maximum power dissipation as a function of case temperature
 $(T_j \leq 150^\circ\text{C})$

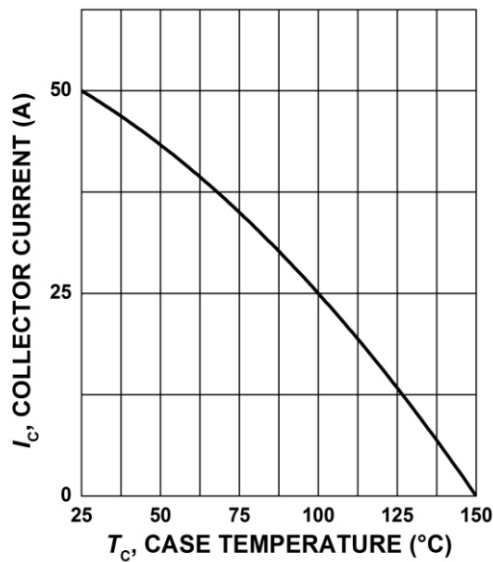


Figure 3. Maximum collector current as a function of case temperature
 $(V_{GE} \geq 15\text{V}, T_j \leq 150^\circ\text{C})$

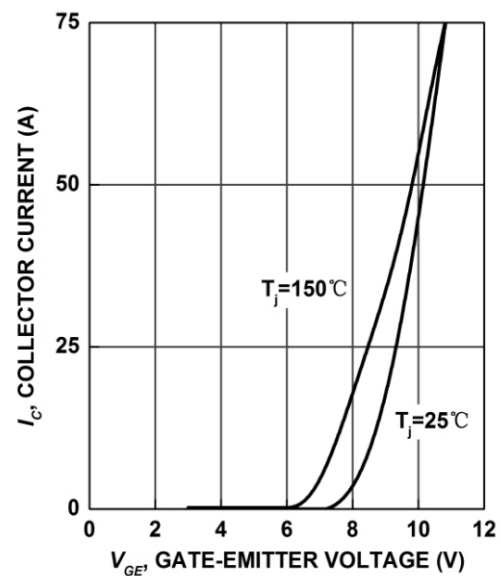


Figure 4. Typical transfer characteristic
 $(V_{CE} = 15\text{V})$

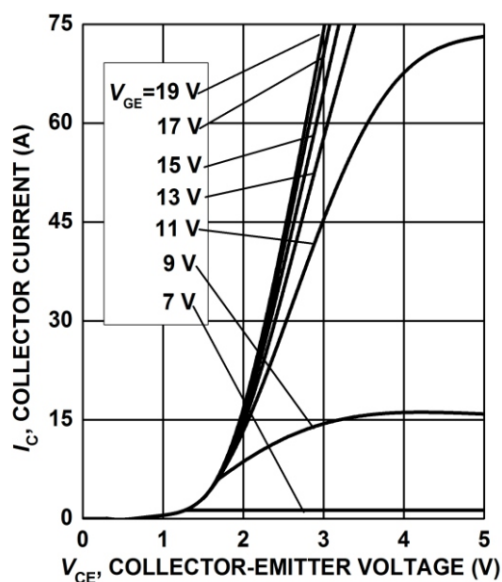


Figure 5. Typical output characteristic
($T_j = 25^\circ\text{C}$)

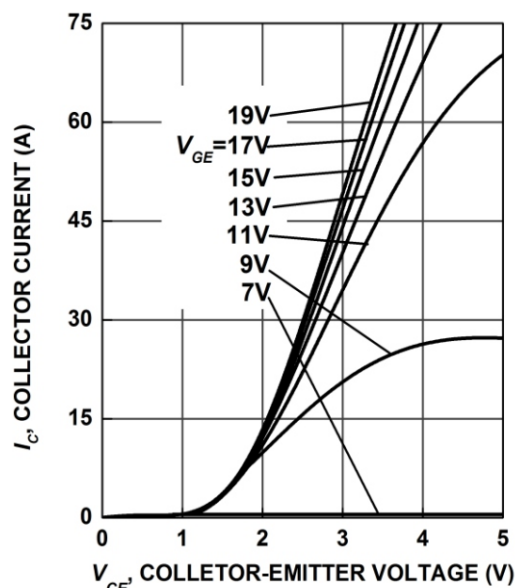


Figure 6. Typical output characteristic
($T_j = 150^\circ\text{C}$)

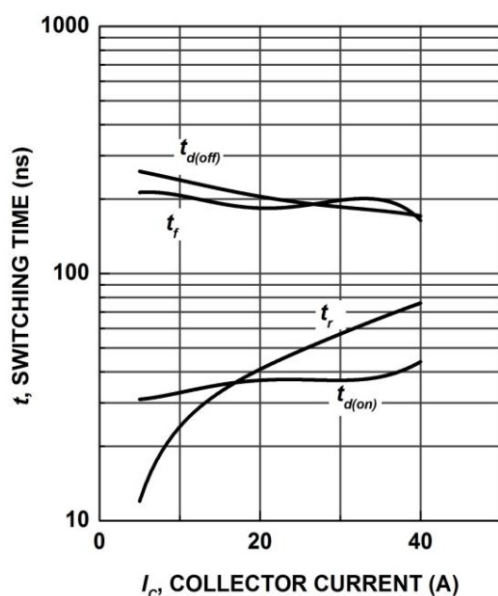


Figure 7. Typical switching times as a function of collector current
(inductive load, $T_j=150^\circ\text{C}$, $V_{CE}=600\text{V}$, $V_{GE}=0/15\text{V}$, $R_G=15\Omega$, Dynamic test circuit in Figure D)

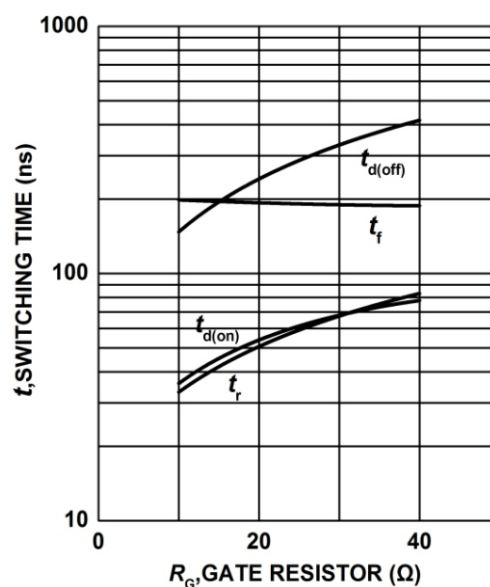


Figure 8. Typical switching times as a function of gate resistor
(inductive load, $T_j=150^\circ\text{C}$, $V_{CE}=600\text{V}$, $V_{GE}=0/15\text{V}$, $I_C=25\text{A}$, Dynamic test circuit in Figure D)

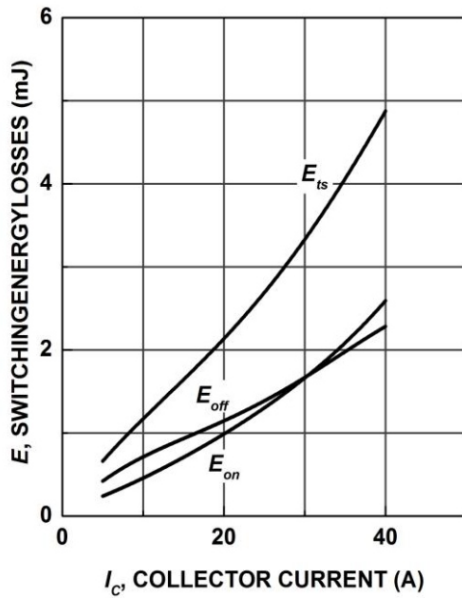


Figure 9. Typical switching energy losses as a function of collector current
(inductive load, $T_j=150^\circ\text{C}$, $V_{CE}=600\text{V}$,
 $V_{GE}=0/15\text{V}$, $R_G=15\Omega$,
Dynamic test circuit in Figure D)

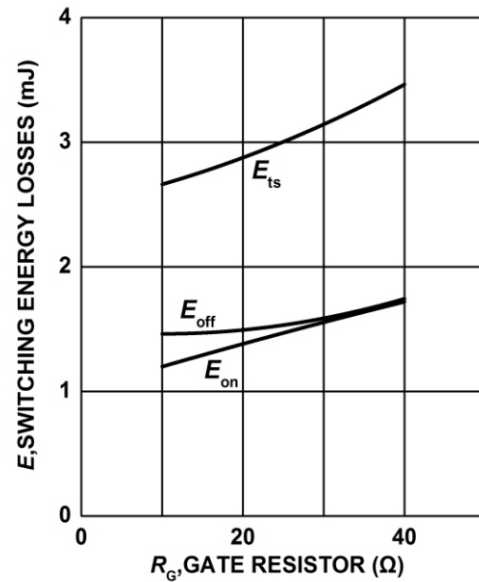


Figure 10. Typical switching energy losses as a function of gate resistor
(inductive load, $T_j=150^\circ\text{C}$, $V_{CE}=600\text{V}$,
 $V_{GE}=0/15\text{V}$, $I_C=25\text{A}$,
Dynamic test circuit in Figure D)

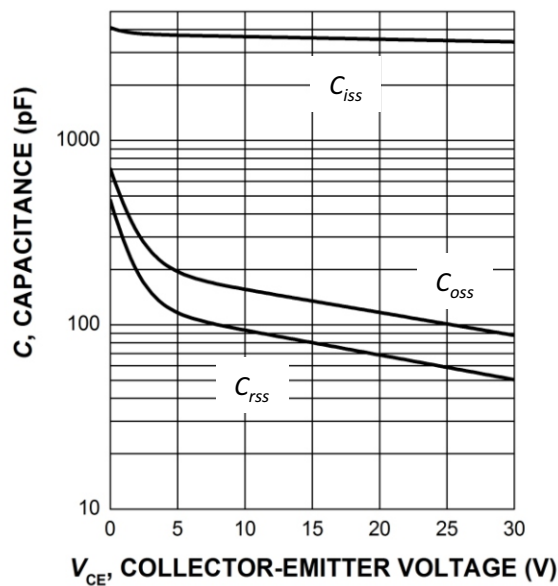


Figure 11. Typical capacitance as a function of collector-emitter voltage
($V_{GE}=0\text{V}$, $f = 1\text{ MHz}$)

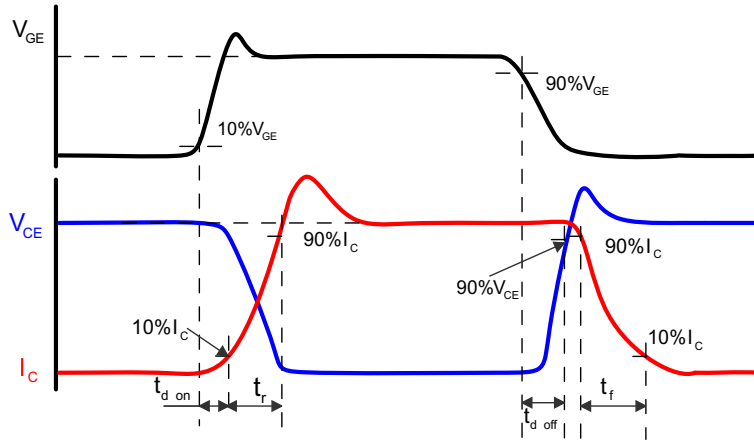


Figure A. Definition of switching times

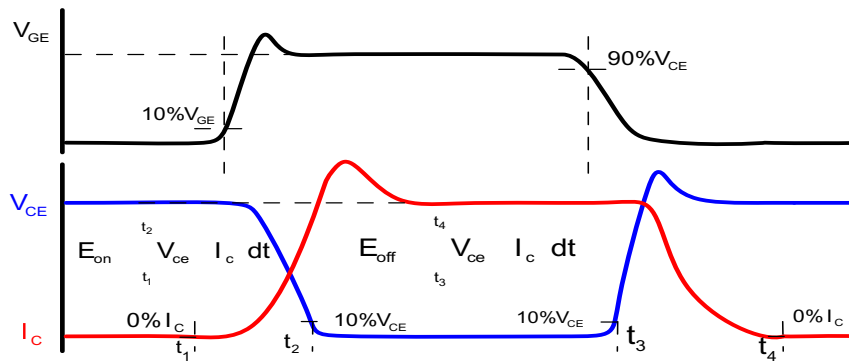


Figure B. Definition of switching losses

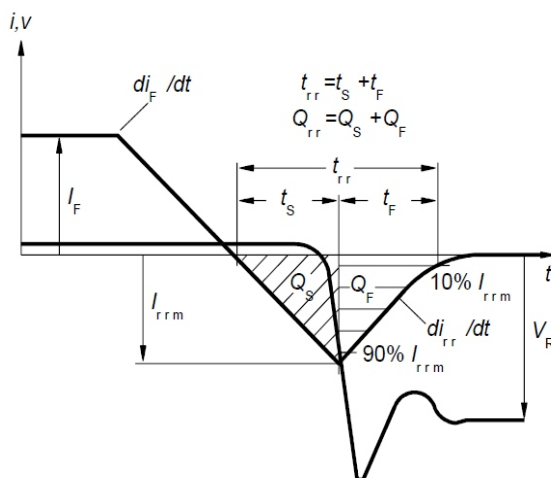


Figure C. Definition of diodes switching characteristics

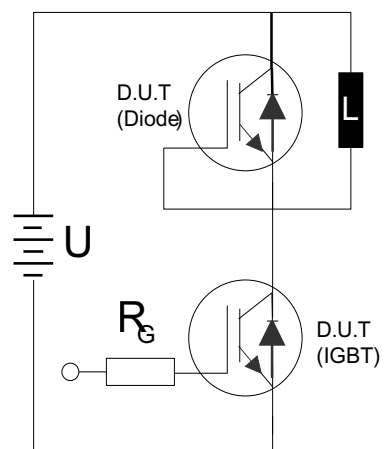


Figure D. Dynamic test circuit

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